



**ALPHA & OMEGA**  
SEMICONDUCTOR, LTD

**AON4413**

**P-Channel Enhancement Mode Field Effect Transistor**

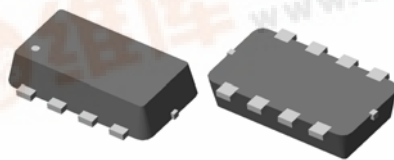


### General Description

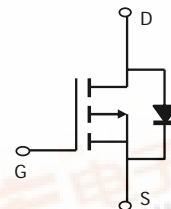
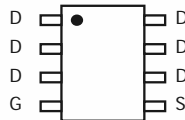
The AON4413 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use as a load switch or in PWM applications. *Standard product AON4413 is Pb-free (meets ROHS & Sony 259 specifications).*

### Features

$V_{DS}$  (V) = -30V  
 $I_D$  = -6.5A ( $V_{GS}$  = -10V)  
 $R_{DS(ON)}$  < 46m $\Omega$  ( $V_{GS}$  = -10V)  
 $R_{DS(ON)}$  < 60m $\Omega$  ( $V_{GS}$  = -6V)



DFN 3x2



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	10 Sec	Steady State	Units
Drain-Source Voltage	$V_{DS}$	-30		V
Gate-Source Voltage	$V_{GS}$	$\pm 20$		V
Continuous Drain Current <sup>A</sup>	$T_A=25^\circ\text{C}$	-6.5	-4.7	A
	$T_A=70^\circ\text{C}$	-5.3	-3.7	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	-25		
Power Dissipation <sup>A</sup>	$T_A=25^\circ\text{C}$	3.1	1.6	W
	$T_A=70^\circ\text{C}$	2.0	1.0	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150		$^\circ\text{C}$

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	34	40	$^\circ\text{C/W}$
Maximum Junction-to-Ambient <sup>A</sup>		66	80	$^\circ\text{C/W}$
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	20	25	$^\circ\text{C/W}$

Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> = -250μA, V <sub>GS</sub> = 0V	-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V T <sub>J</sub> = 55°C			-1 -5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.5	-2	-2.5	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -5V	-25			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10V, I <sub>D</sub> = -6.5A T <sub>J</sub> = 125°C		38 54	46 65	mΩ
		V <sub>GS</sub> = -6V, I <sub>D</sub> = -5.3A		48	60	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -5V, I <sub>D</sub> = -6.5A		11		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> = -1A, V <sub>GS</sub> = 0V		0.77	-1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-3	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V, f=1MHz		668	830	pF
C <sub>oss</sub>	Output Capacitance			126		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			92		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		6	9	Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub> (10V)	Total Gate Charge (10V)	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-6.5A		12.7	17	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)			6.4	8.5	nC
Q <sub>gs</sub>	Gate Source Charge			2		nC
Q <sub>gd</sub>	Gate Drain Charge			4		nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, R <sub>L</sub> =2.3Ω, R <sub>GEN</sub> =3Ω		7.7		ns
t <sub>r</sub>	Turn-On Rise Time			6.8		ns
t <sub>D(off)</sub>	Turn-Off DelayTime			20		ns
t <sub>f</sub>	Turn-Off Fall Time			10		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6.5A, dI/dt=100A/μs		22	30	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-6.5A, dI/dt=100A/μs		15		nC

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> = 25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using < 300 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

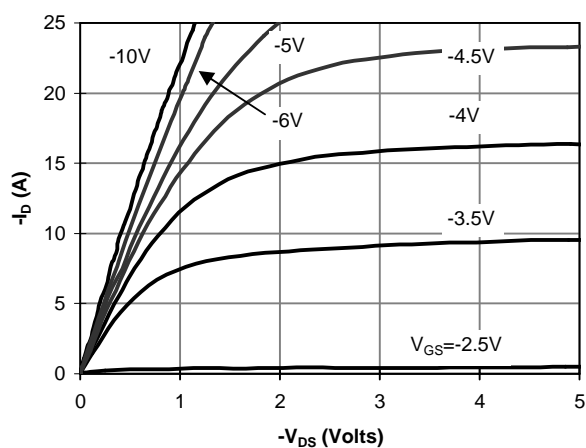


Figure 1: On-Region Characteristics

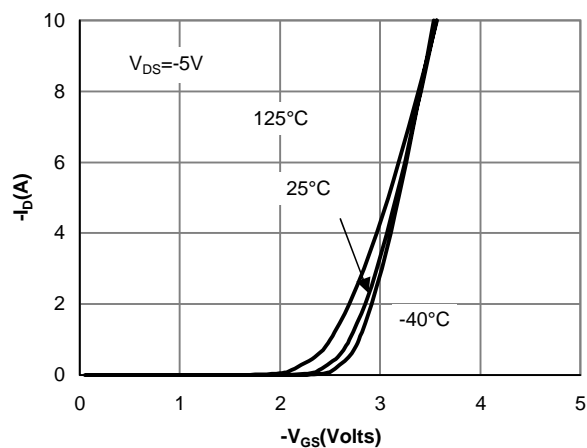


Figure 2: Transfer Characteristics

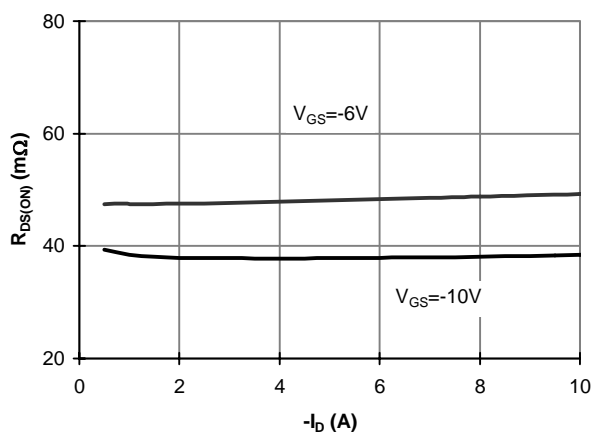


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

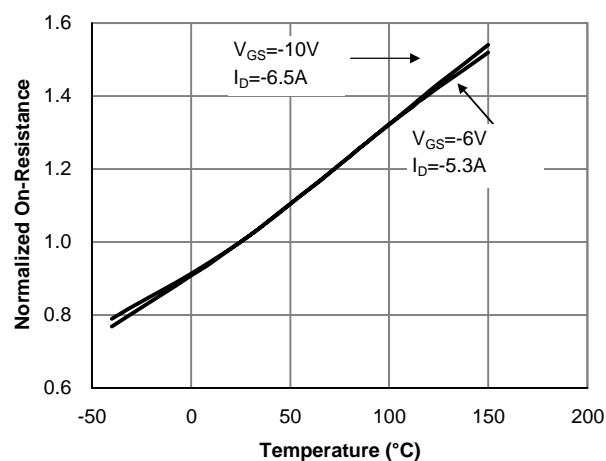


Figure 4: On-Resistance vs. Junction Temperature

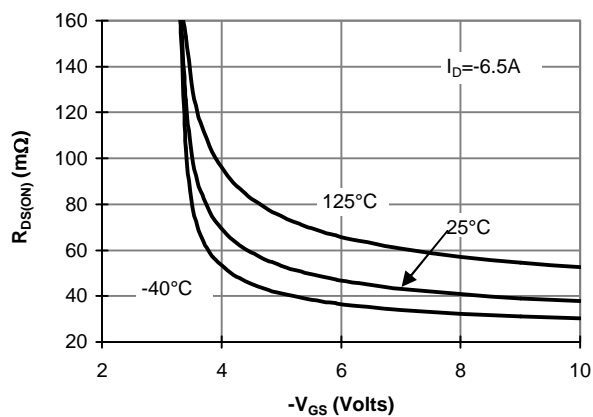


Figure 5: On-Resistance vs. Gate-Source Voltage

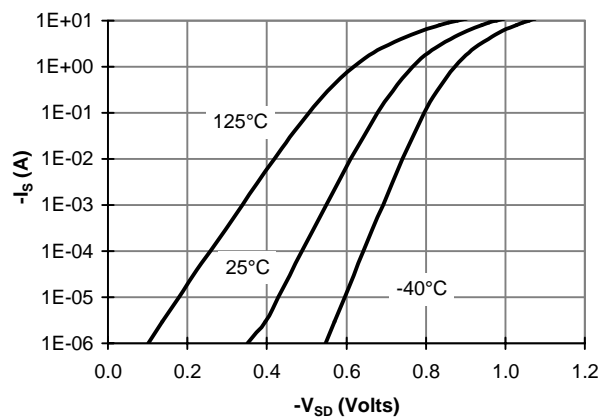


Figure 6: Body-Diode Characteristics

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